

SEP 2 4 2004

O.S. DEPARTMENT OF COMMERCE PATENTEAND TRADEMARK OFFICE

APPLN. NO. DOCKET NO. 10/779,292 LT-171 **APPLICANT** CONFIRMATION NO. 7415 Florin Oprescu FILING DATE **GROUP ART UNIT** February 12, 2004 2819

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Byta	4,684,925	08/04/97	Maruta	341	143	
7.7	4,704,600	11/03/87	Uchimura et al.	340	347	
	4,876,542	10/24/89	Van Bavel et al.	341	143	
	4,876,544	10/24/89	Kuraishi	341	166	
	5,010,347	04/23/91	Yukawa	341	143	
	5,148,167	09/15/92	Ribner	341	143	
	5,396,245	03/07/95	Rempfer	341	145	
	5,450,083	09/12/95	Brewer	341	143	,
	5,675,334	10/07/97	McCartney	341	118	
	5,870,048	02/09/99	Kuo et al.	341	143	
	5,982,315	11/09/99	Bazarjani et al.	341	143	
	6,037,887	03/14/00	Wu et al.	341	143	
	6,057,793	5/02/00	Gong et al.	341	143	
	6,198,417	03/06/01	Paul	341	143	
$\overline{\mathbb{V}}$	6,271,782	08/07/01	Steensgaard- Madsen	341	143	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) **EXAMINER** INITIAL Damien McCartney et al., "A Low-Noise Low Drift Transducer ADC," IEEE J. solid State Circuits, 32(7):959-967 (Jul. 1997).

EXAMINER

applicant.

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609, Draw line through citation if not conformance and not considered. Include copy of this form with next communication to **FORM PTO-1449**

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EXAMINER INITIAL	
my	Donald A. Kerth et al., "An Oversamplint Converter for Strain Gauge Transducers," IEEE J. Solid State Circuits, 27(12): 1689-96 (Dec. 1992).
m	"16-Bit/20-Bit Multi-Range ADC x/4-Bit Latch," Crystal Semiconductor Corporation 1996.
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